

Date Created : 2007/11/28
Date Issued On : 2007/12/05
PCN# : Q4074807

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

Technical Contact:

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PCN Originator:

Name: Kalabkova, Ivana
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Phone: 408-822-2187

Implementation of change:

Expected 1st Device Shipment Date: 2008/03/02

Earliest Year/Work Week of Changed Product: 0810

Change Type Description: Die Revision

Description of Change (From): Current die size: 76x38

Description of Change (To): New die size: 83x40

Reason for Change : The mask set for this device was modified to improve the Rg performance of the part from a typical of 9 Ohms to 4.5 Ohms.

Qual/REL Plan Numbers : Q20050144

Qualification :

All qualification tests passed the defined qualification plan requirement.

Results/Discussion

Test: (High Temperature Reverse Bias)					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20050144AAHTRB	FDS6681Z	0/79			
			0/79		
				0/79	
Q20050144ABHTRB		0/79			
			0/79		
				0/79	

Test: 130C (Highly Accelerated Stress Test)			
Lot	Device	96-HOURS	Failure Code
Q20050144AAHAST1	FDS6681Z	0/79	

Q20050144ABHAST1	FDS6681Z	0/79	
Test: MSL(1), PKG(Small), PeakTemp(260c), Cycles(3) (Precondition)			
Lot	Device	Results	Failure Code
Q20050144AAPCNL1A	FDS6681Z	0/79	
Q20050144ABPCNL1A	FDS6681Z	0/79	

Product Id Description : Fairchild Semiconductor's selected products in the NMSON package. Products affected by this change are listed below in the "Affected FSIDs" section.

Affected FSIDs :

FDS4935BZ	FDS4935BZ_SBME002	
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